Application/Control No. Applicant(s)/Patent Under Reexamination 10/646,793 PAN ET AL. Notice of References Cited **Examiner** Art Unit Page 1 of 1 Patricia Leith 1655 **U.S. PATENT DOCUMENTS Document Number** Date Name Classification Country Code-Number-Kind Code MM-YYYY US-Α US-В US-C US-D US-Ε US-US-G US-Н US-US-US-US-US-**FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Bang et al. KR 2001102650 A 11-2001 KR N KR 2002090175 A 11-2002 KR Kim, H. 0 Р Q R S **NON-PATENT DOCUMENTS** * Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) V W X

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